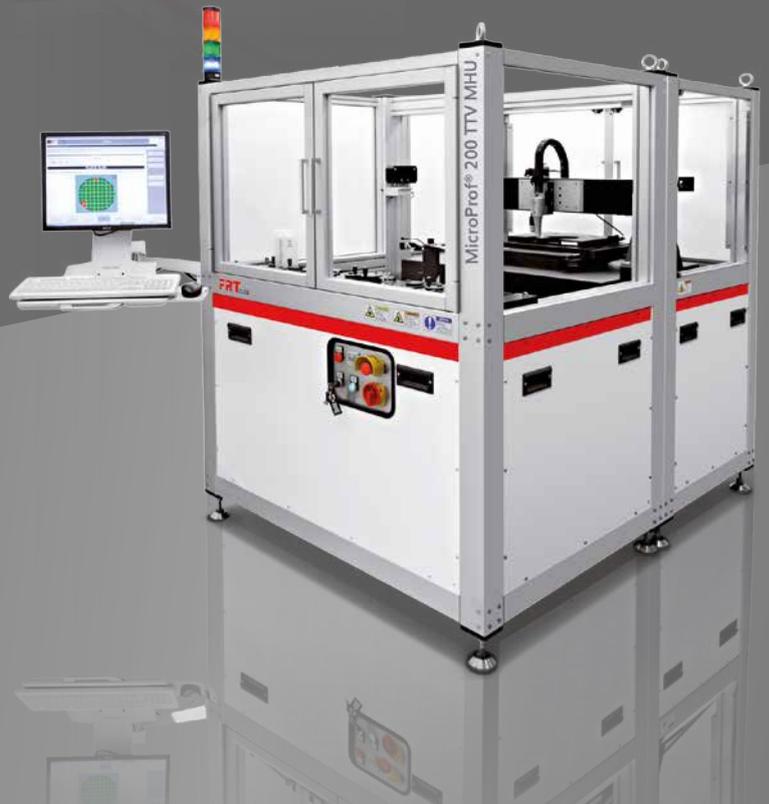


3D SURFACE METROLOGY
SYSTEMS FOR RESEARCH
AND PRODUCTION

FRT
THE ART OF
METROLOGY™

The MicroProf®- Series

Non-contact and non-destructive measurement of
roughness, profiles, topography and film thickness





THE MICROPROF® – ONE SURFACE METROLOGY TOOL

MAXIMUM FLEXIBILITY THANKS TO MULTI-SENSOR TECHNOLOGY

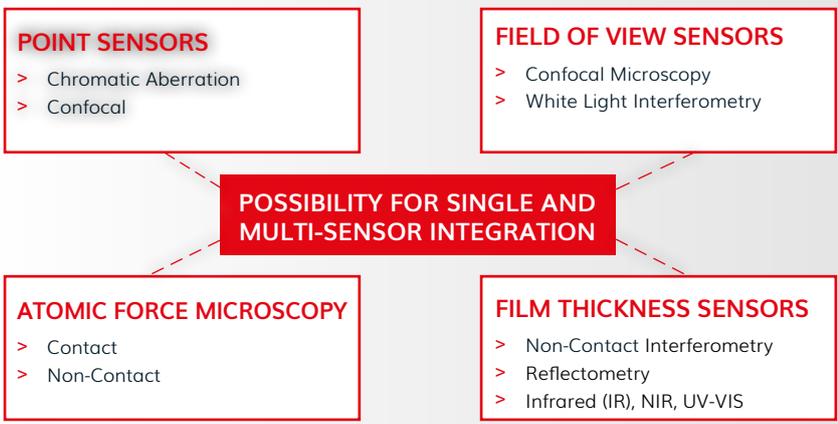
The MicroProf® from FRT makes it easy to perform diverse measurement tasks quickly, efficiently and intuitively. As an established standard measuring system in modern 3D surface metrology, the MicroProf® has been impressing our customers for example in the semiconductor, medical and automotive industries for many years. Whether you want to measure the topography, thickness or film thickness of your samples contactfree, the versatile MicroProf® can be used universally thanks to proven optical FRT multi-sensor technology. Different optical measurement methods which are only available elsewhere as individual solutions have been combined into a universal, space-saving device.

Depending on your requirements, the MicroProf® enables you to perform quick overview measurements of the entire sample as well as high-resolution detailed measurements. This is made possible thanks to the various combinations of the measuring sensors. In addition, FRT's proprietary software can be configured individually and your measurement tasks implemented either manually or automatically.

Retain flexibility for your future sample measurements and upgrade sensors easily and quickly as required, saving space, time and (not least) expense.

MEASURING TASKS

Roughness	Step Height	Film Thickness	Profile	Wear Volume	
3D Map	Roll-off Amount	TTV	Thickness	Waviness	Bow
Membrane Bow	Layer Stacks	Defect Size	Topography	Angle	
Warp	Vias / TSV	Bumps	Flatness	Critical Dimension	Slope
Radius of Curvature	Grain Size	Coplanarity	...		



TOOL FOR ALL MEASURING TASKS

SUITABLE FOR ANY SAMPLE SIZE

The MicroProf® universal surface metrology tool is available in different versions. Depending on the size of the samples to be measured, you can choose the system which provides the appropriate sample holder and travel distance. In addition to the MicroProf® 100 tabletop unit, there are two larger models, MicroProf® 200 and MicroProf® 300 which are standalone systems. For these two variants, the Material Handling Unit (MHU) is also available. From manual measurement and evaluation through to fully automated execution of sample handling, measurement and evaluation, you can determine the degree of automation yourself by selecting the appropriate software and hardware components.

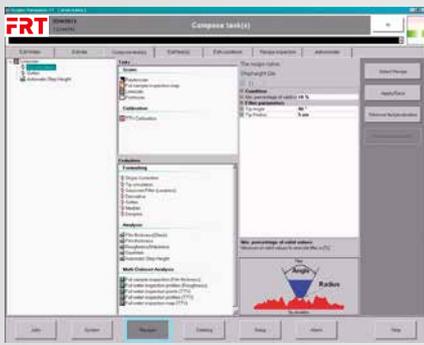


	MicroProf® 100	MicroProf® 200	MicroProf® 300
xy-Travel *	150 mm x 100 mm	250 mm x 200 mm	415 mm x 305 mm
Multi-Sensor	X	X	X
TTV-Option	X	X	X
Tabletop Unit	X		
Standalone		X	X
Automation (optional)	X	X	X
Sample handling (optional)		X	X
Thermo Unit (optional)	X	X	X

BOTH SIDES CONSIDERED

Both the tabletop unit and the standalone systems in the MicroProf® series include the option for two-sided sample inspection (TTV option). This enables you to measure the top and bottom of your sample simultaneously and determine the sample thickness during the same measurement process. The thickness variation (TTV – total thickness variation) of the sample can be determined along with surface parameters, e.g. the roughness, waviness and flatness of both surfaces or the parallelism of the two sides. The TTV option can be easily retrofitted at your site.

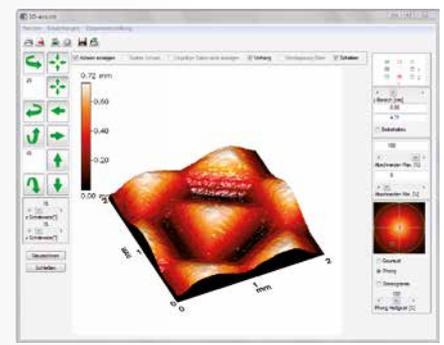




Recipe creation – process definition:
FRT Acquire Automation XT



Automated measurement process
sequence: FRT Acquire Automation XT



3D view of a measurement FRT Mark III

SOFTWARE MADE BY FRT

INTUITIVE MEASUREMENT – FRT ACQUIRE

In simple steps, the FRT Acquire software walks you through manual measurements, from switching the device on to execution of the measurement process. FRT Acquire's structured user guidance enables you to easily perform manual measurements of all kinds. All sensors in use on your MicroProf® can be controlled via the software's user interface. Whether point, profile or 3D measurements are needed, simply set the optimum measurement parameters for your application, monitor them via the intuitive live display and easily save your measured data subsequently.

AUTOMATED MEASUREMENT AND EVALUATION – FRT ACQUIRE AUTOMATION XT

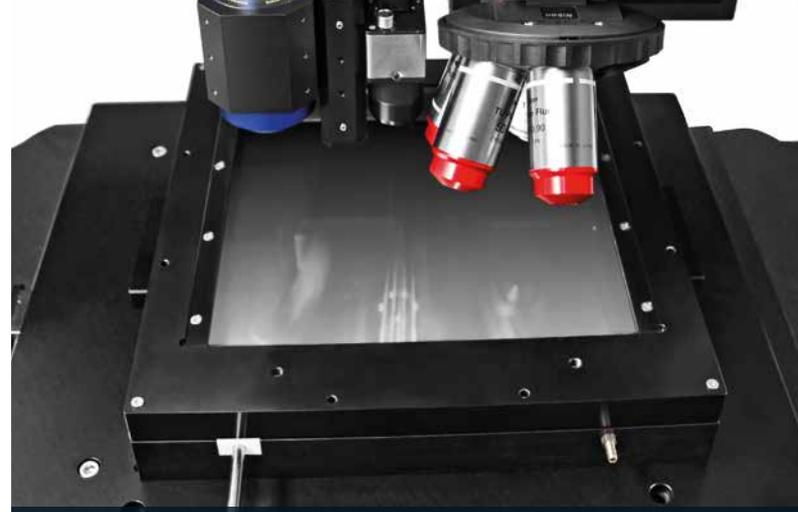
Fully automated execution and evaluation of measurements is possible with the recipe-based software FRT Acquire Automation XT. This software provides comprehensive capabilities, from manual measurement on the device to fully automated measurement with one-button operation and integration into production control systems, e.g. via a SECS/GEM interface. Choose the suitable measurement and evaluation routine for your measuring task from a variety of packages. For recurring structures, a layout wizard with a graphical user interface (GUI) can support you in learning the measuring positions. In addition, fine sample alignment via pattern recognition is available as an option. You can easily configure various measurement tasks using different sensors to run consecutively as a measurement sequence. This includes the execution of measurements, processing and analysis using intelligent algorithms, output and visualization of results in the form of reports and the export of results in various data formats. The current DIN-EN-ISO and industry-specific standards such as SEMI are complied with as a matter of course. With its SEMI-compliant user interface, the FRT Acquire Automation XT satisfies all requirements for use both in production and the laboratory. And naturally, the software contains user administration functions including assignment of individual user rights.

COMPREHENSIVE EVALUATION – FRT MARK III

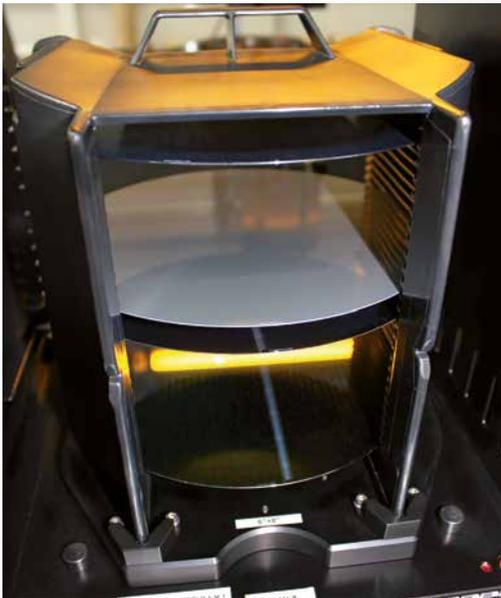
The FRT Mark III analysis software provides a comprehensive package for the processing, evaluation and presentation of your 2D or 3D measurements. The latest standards are implemented, including roughness and waviness calculation, as well as many processing and filter functions. Choose the appropriate analysis functions for your application from the wide range of options, including roughness, flatness, step height, film thickness and many more. Present your results in 3D, as a profile view or top view, and design your own measurement protocols. This user-friendly software also contains diverse import and export capabilities and can automatically execute multiple processing and evaluation steps in your measurement series.



MHU – MATERIAL HANDLING UNIT



THERMO UNIT



SAMPLE HANDLING

In many industries, it is necessary to connect high sample throughput rates to automated measurement processes. For this purpose, automatic handling of samples is required.

The MHU option for the semiconductor, MEMS and LED industries enables fully automatic measurements of different samples (wafers) to be easily achieved. From up to 4 cassettes, the MicroProf® analyzes (for example) wafers with a diameter of 2 to 12 inches with full integration in the production workflow and full automation. Optionally, the MHU fitted to the MicroProf® can be equipped for sample sorting of good and bad parts.

Other systems for sample handling, e.g. SCARA robots, can also be integrated.

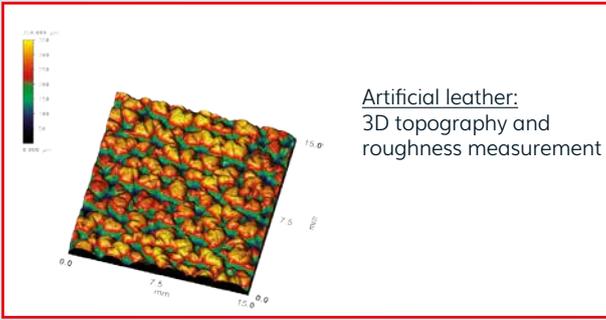


SURFACE MEASUREMENTS UNDER TEMPERATURE INFLUENCE

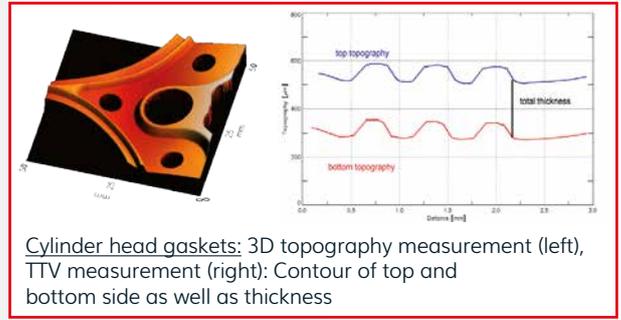
Changes to components due to thermal stress can lead to functional impairments or even failures. The topographical assessment of samples under thermal load is critical, e.g. in the areas of electronic components and material technology.

By adding the thermo unit to the MicroProf®, you can perform measurements of the surface topography of components under controlled thermal stress. To do this, the samples to be measured are placed on a heating and cooling plate within a closed chamber (glass cover) and heated. The sample temperature can be precisely adjusted and varied using individually configurable temperature profiles. Both fully automatic measurements of surface topography at different temperatures and dwell times at constant temperatures are fully adjustable. The thermal unit is available as an extension for all FRT measuring devices and is mounted as a separate module just like an ordinary sample holder.

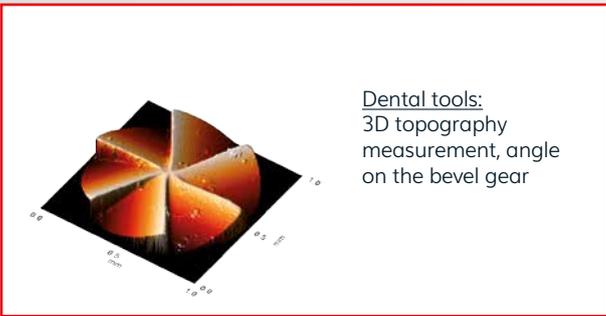
MEASURING EXAMPLES



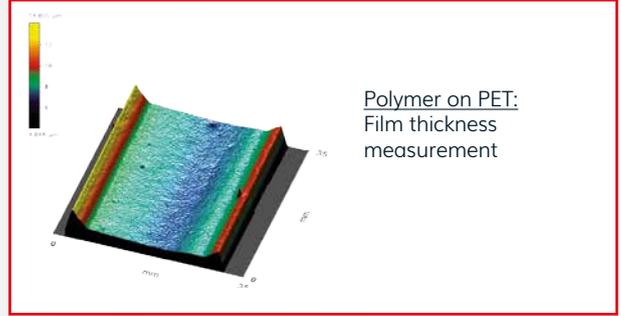
Artificial leather:
3D topography and roughness measurement



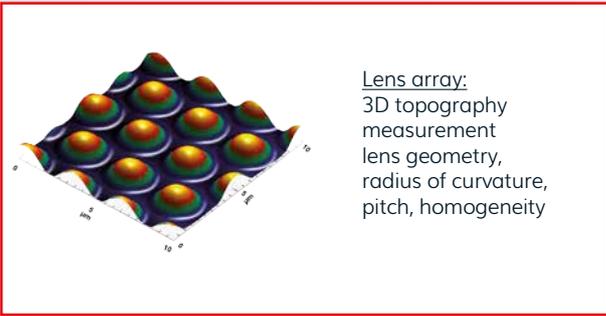
Cylinder head gaskets: 3D topography measurement (left), TTV measurement (right): Contour of top and bottom side as well as thickness



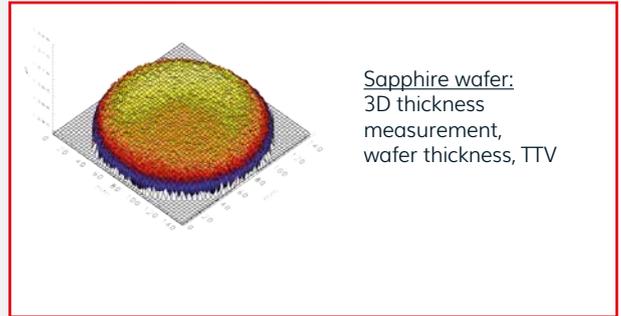
Dental tools:
3D topography measurement, angle on the bevel gear



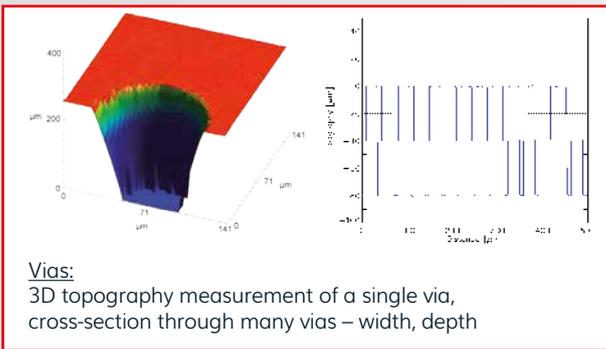
Polymer on PET:
Film thickness measurement



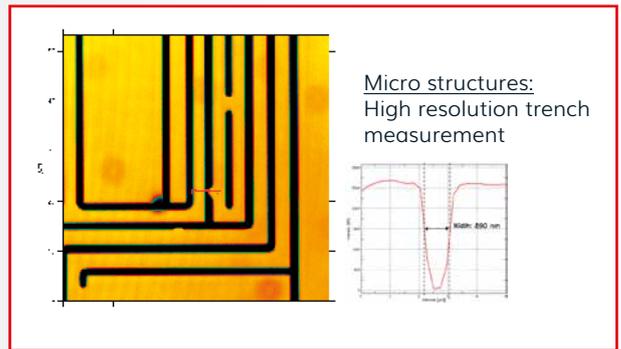
Lens array:
3D topography measurement lens geometry, radius of curvature, pitch, homogeneity



Sapphire wafer:
3D thickness measurement, wafer thickness, TTV



Vias:
3D topography measurement of a single via, cross-section through many vias – width, depth



Micro structures:
High resolution trench measurement

Questions? Talk to an expert!

Germany

FRT GmbH
+49 2204 84-2430
+49 2204 84-2431
info@frt-gmbh.com

Asia / Pacific

FRT Shanghai Co., Ltd.
+86 21 3876 0907
+86 21 3876 0917
info@frt-china.cn

America

FRT of America, LLC (West)
+1 408 261 2632
+1 408 261 1173
info@frtofoamerica.com

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